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(54) **IMAGE SENSOR WITH TRENCHED FILLER GRID WITHIN A DIELECTRIC GRID INCLUDING A REFLECTIVE PORTION, A BUFFER AND A HIGH-K DIELECTRIC**

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H01L 31/0232 (2014.01)
H01L 31/0203 (2014.01)
H01L 27/146 (2006.01)

(52) **U.S. Cl.**
CPC ... **H01L 27/14629** (2013.01); **H01L 27/14627** (2013.01)

(58) **Field of Classification Search**
None
See application file for complete search history.

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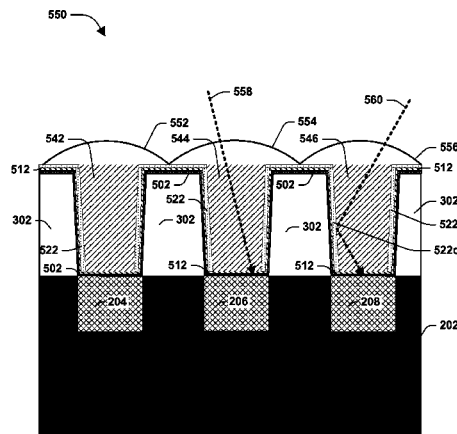
Assistant Examiner — Jay C Chang

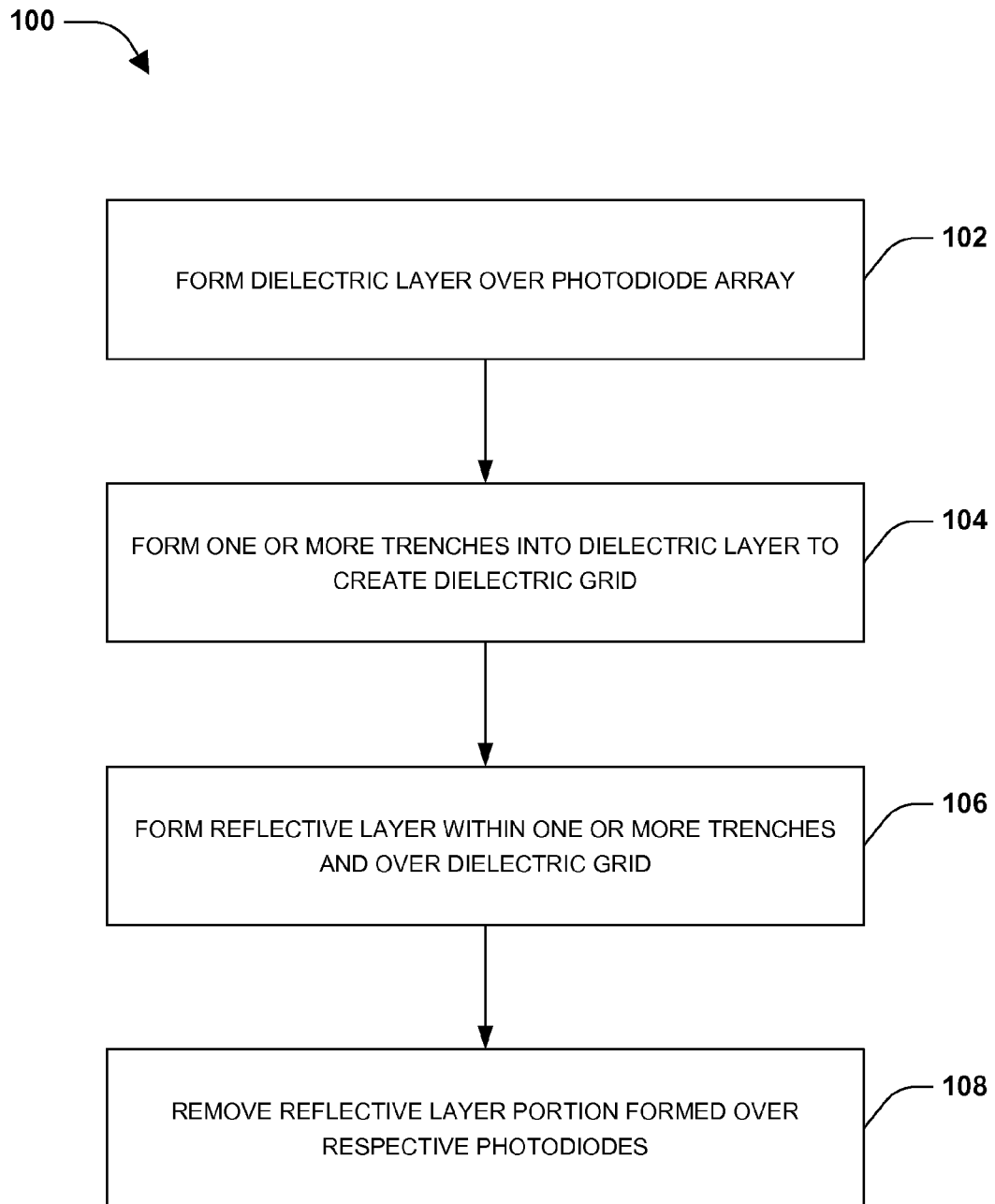
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(57) **ABSTRACT**

Among other things, one or more image sensors and techniques for forming such image sensors are provided. An image sensor comprises a photodiode array configured to detect light. A filler grid is formed over the photodiode array, such as over a dielectric grid. The filler grid comprises one or more filler structures, such as a first filler structure that provides a light propagation path to a first photodiode that is primarily through the first filler structure. In this way, signal strength decay of light along the light propagation path before detection by the first photodiode is mitigated. The image sensor comprises a reflective layer that channels light towards corresponding photodiodes. For example, a first reflective layer portion guides light towards the first photodiode and away from a second photodiode. In this way, crosstalk, otherwise resulting from detection of light by incorrect photodiodes, is mitigated.

20 Claims, 14 Drawing Sheets



**FIG. 1**

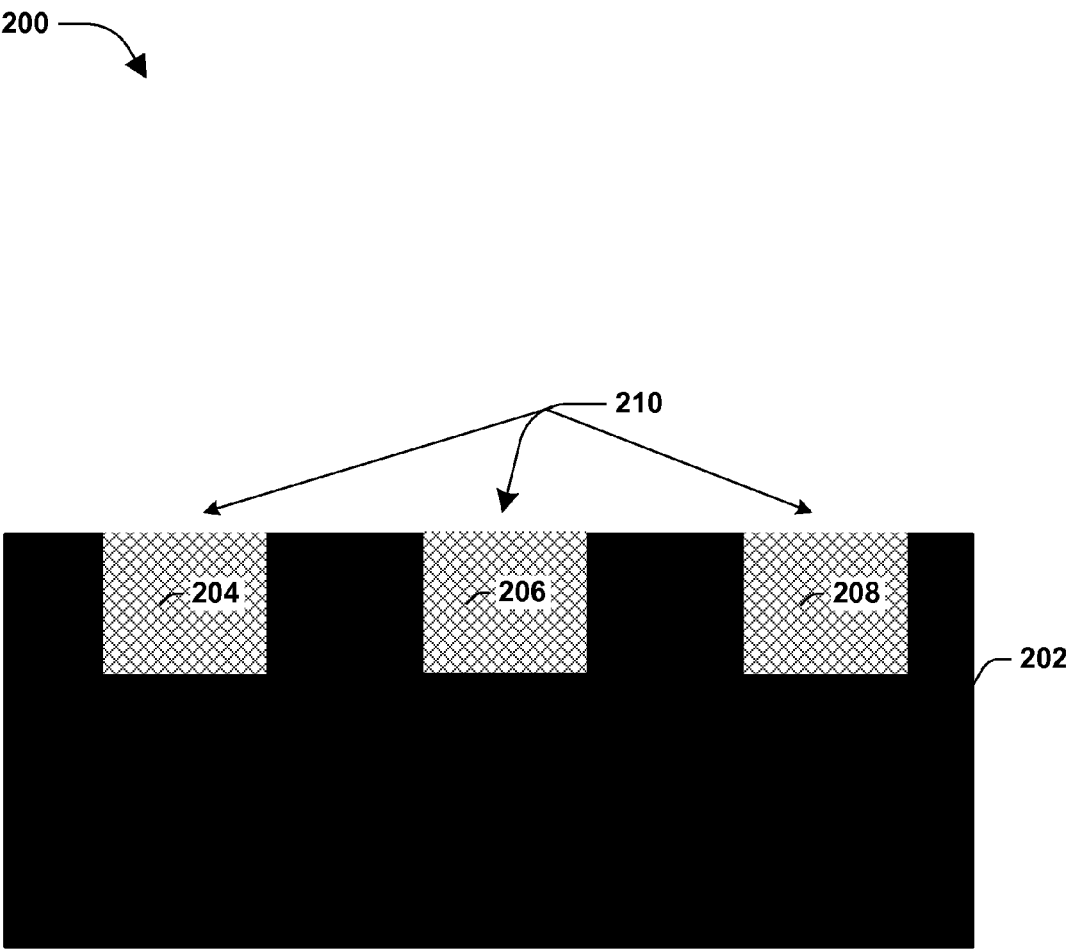


FIG. 2

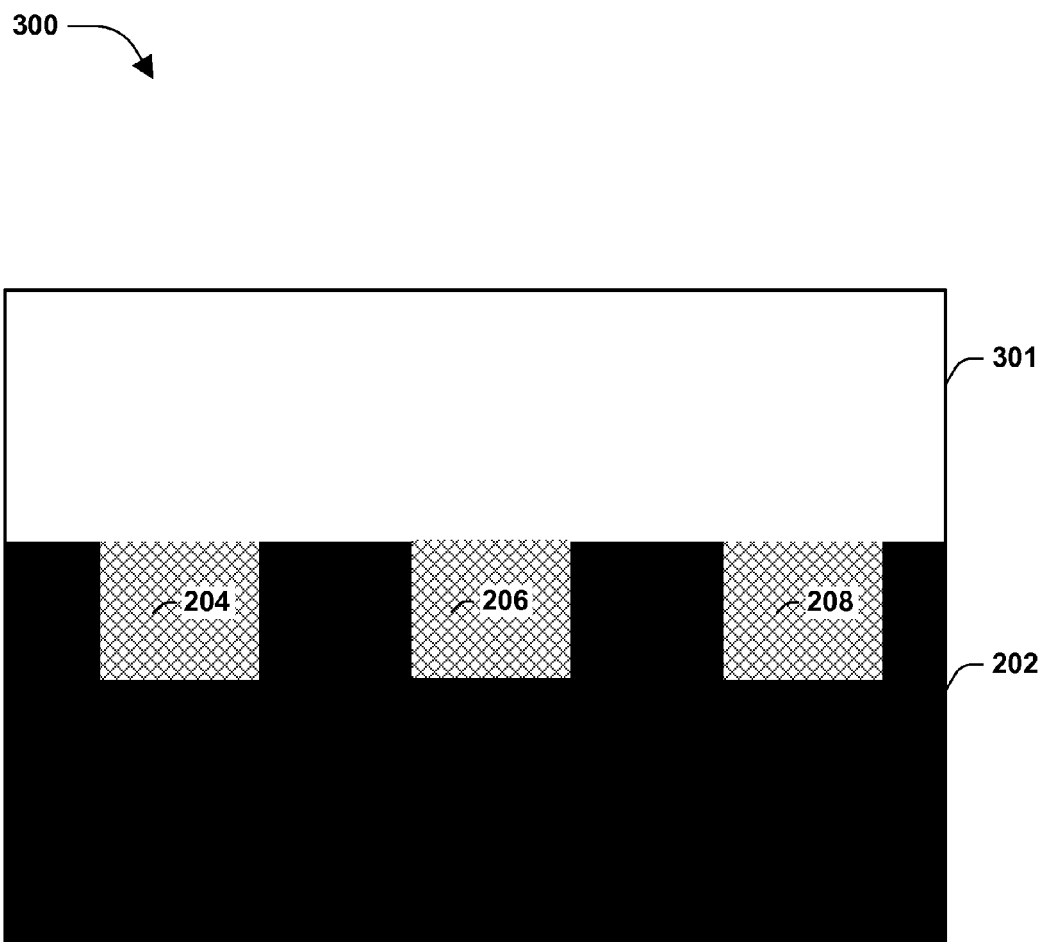


FIG. 3

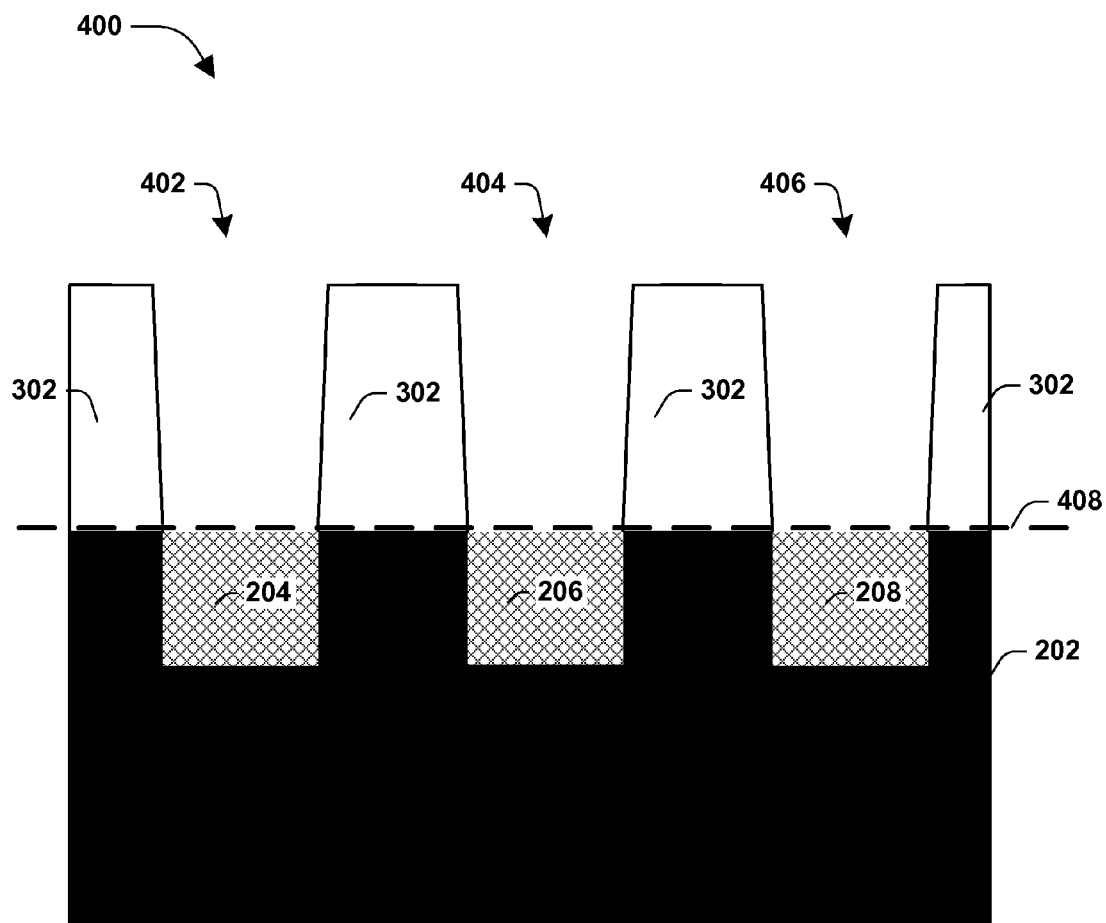


FIG. 4

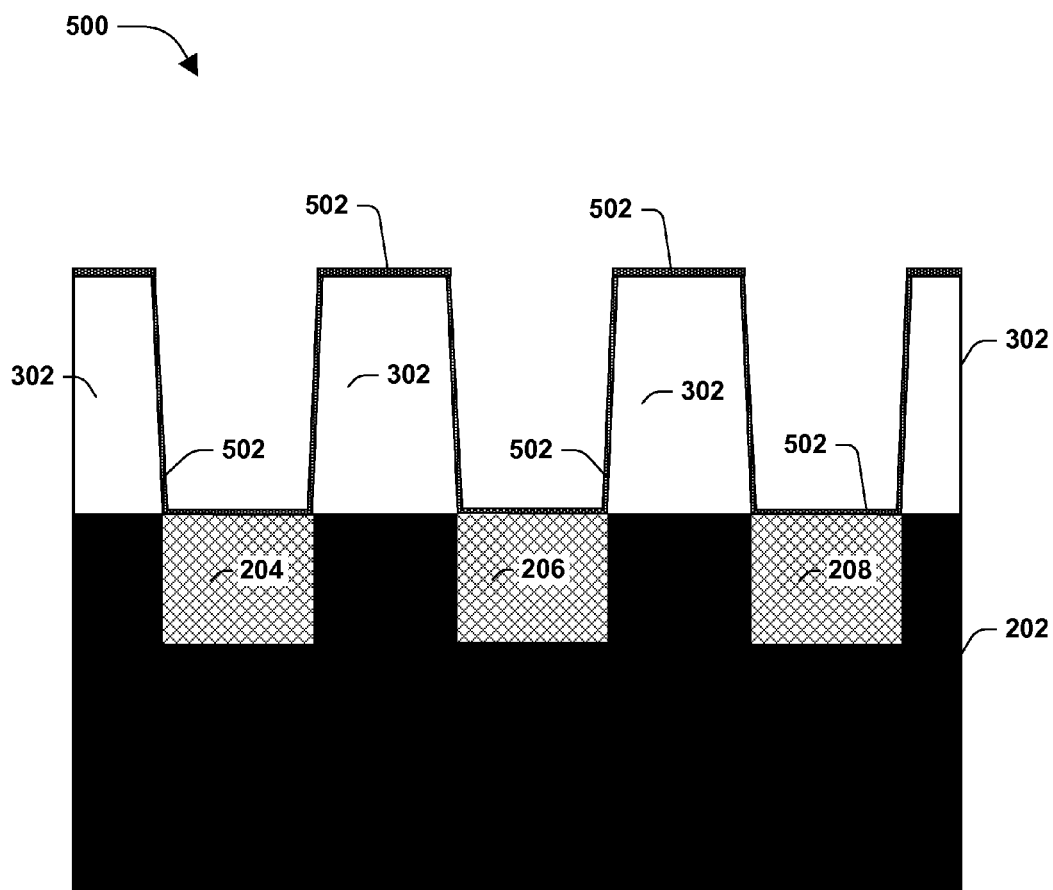


FIG. 5A

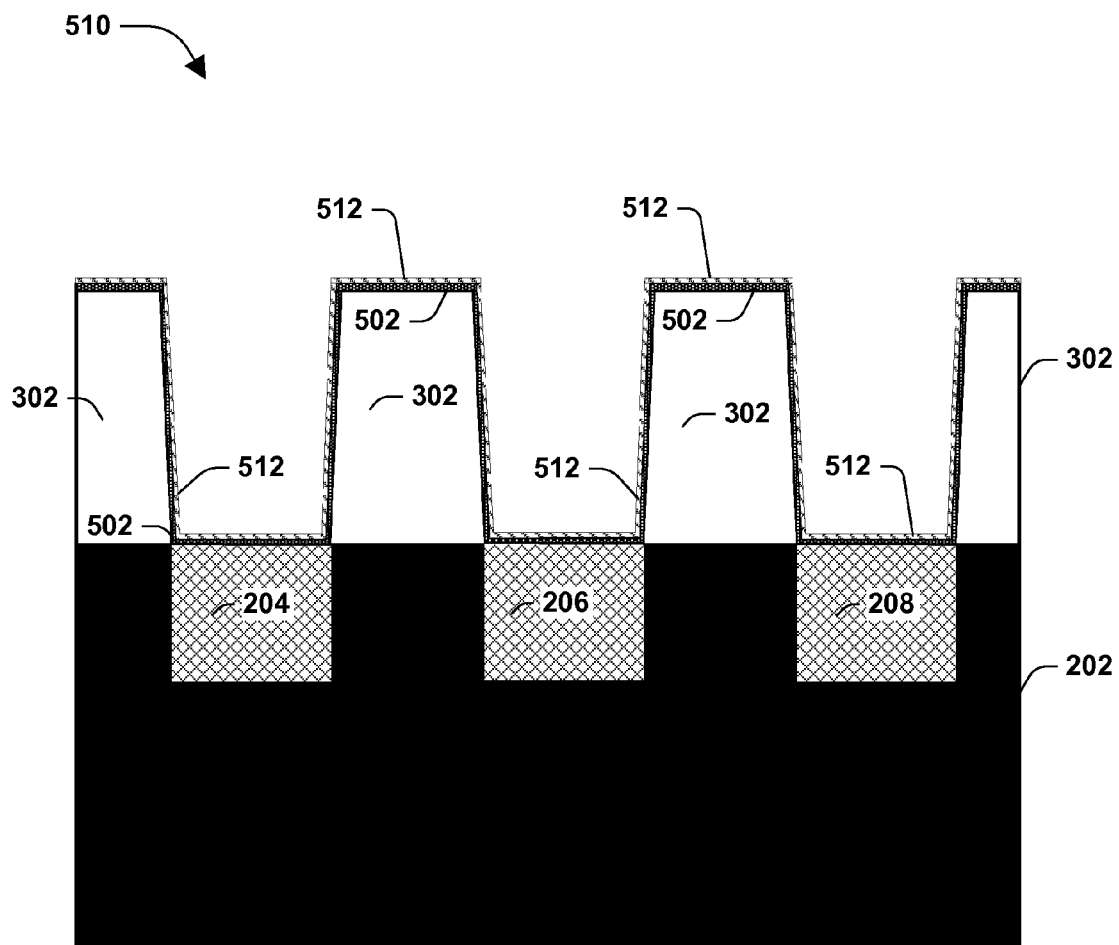


FIG. 5B

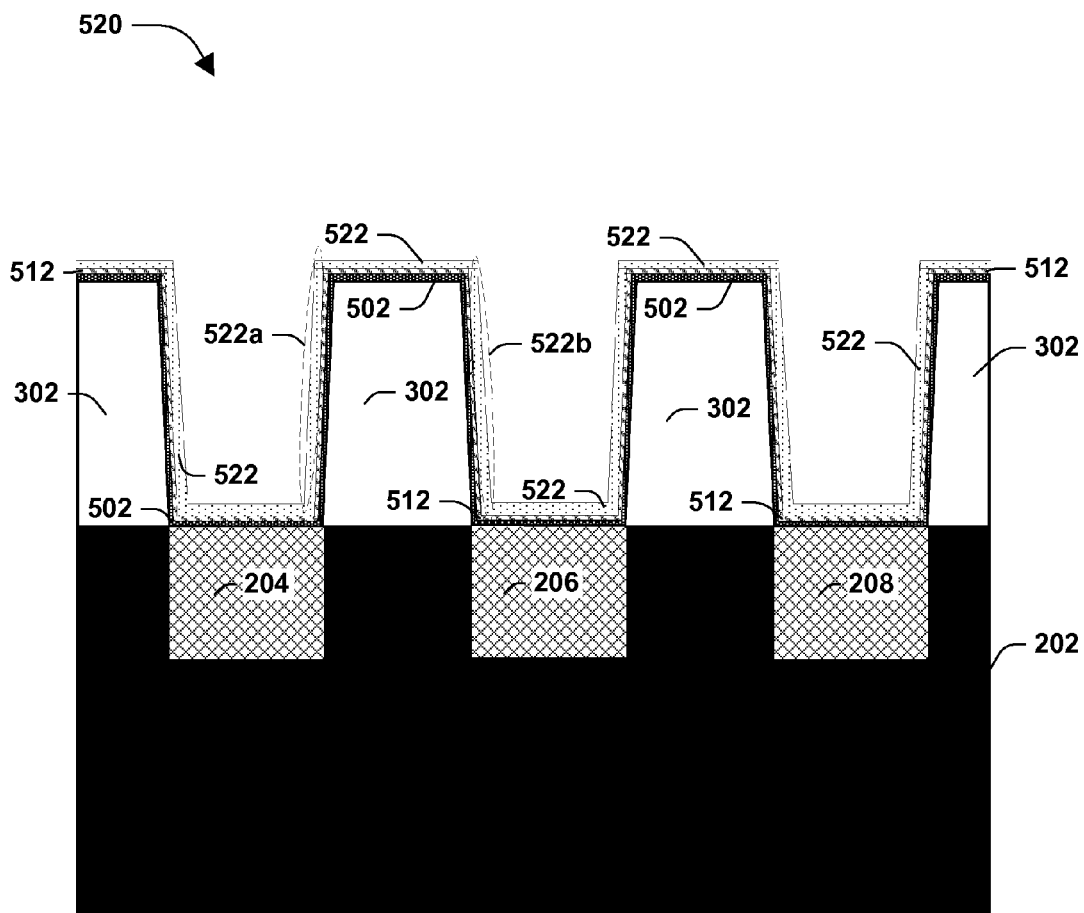


FIG. 5C

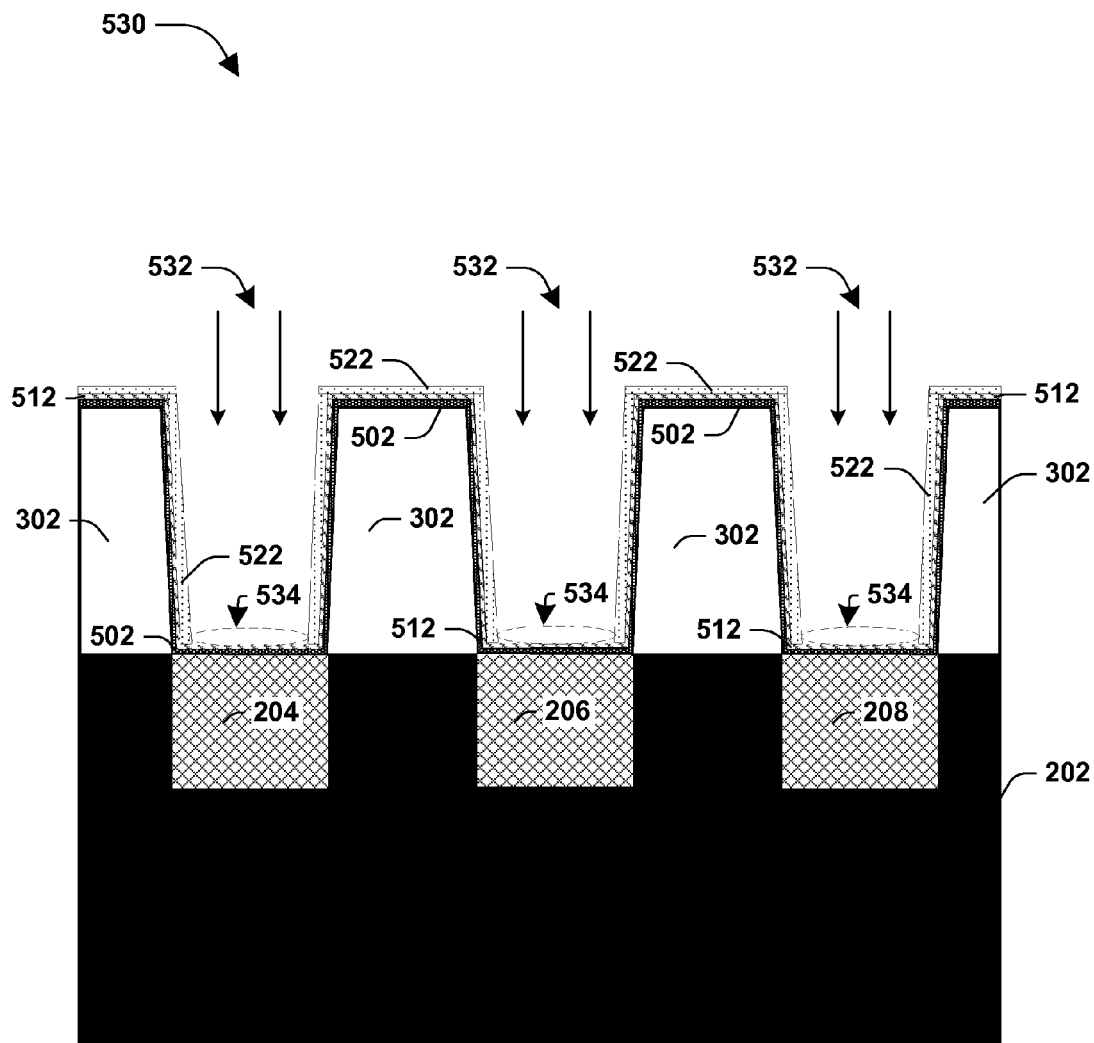


FIG. 5D

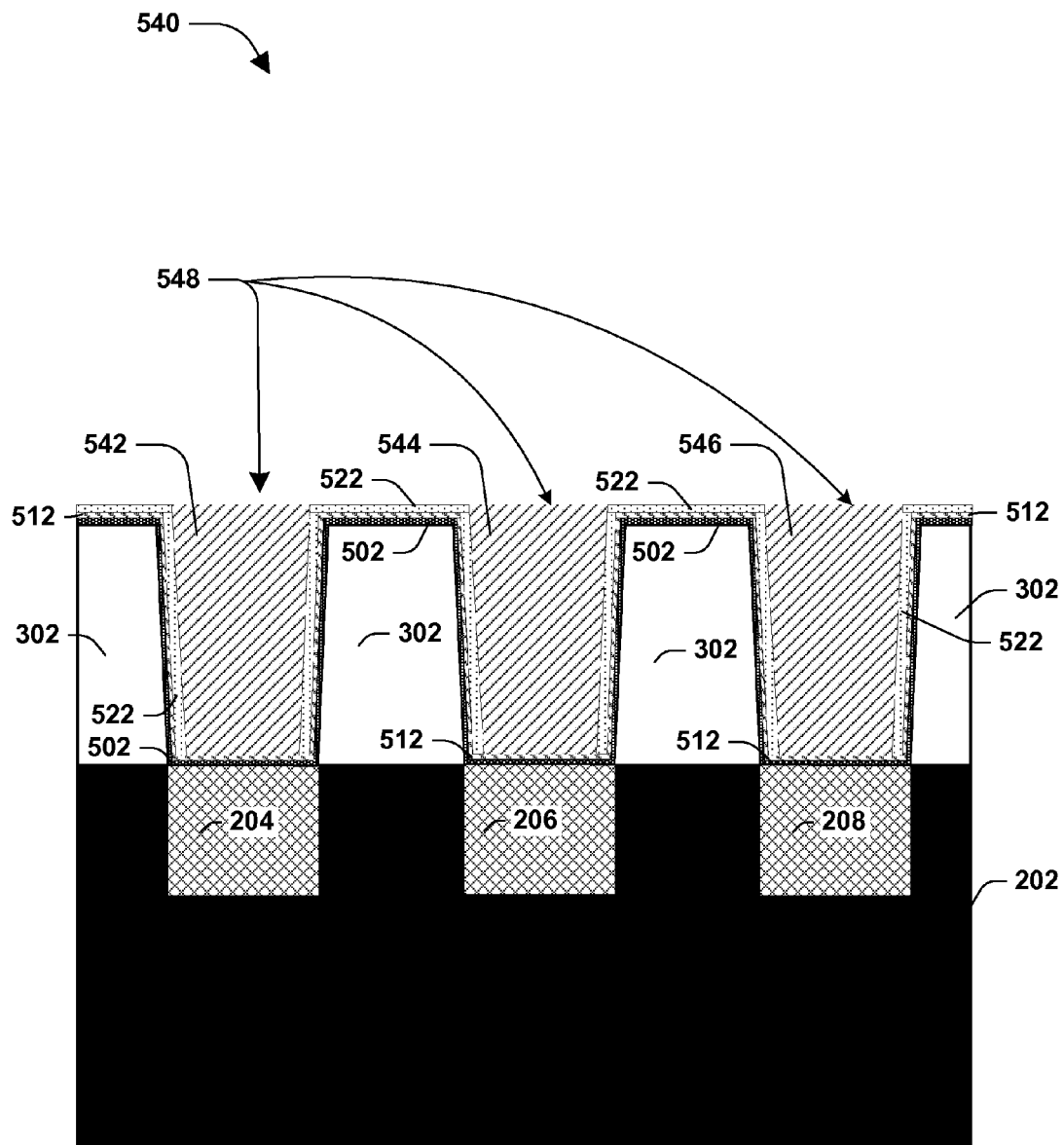


FIG. 5E

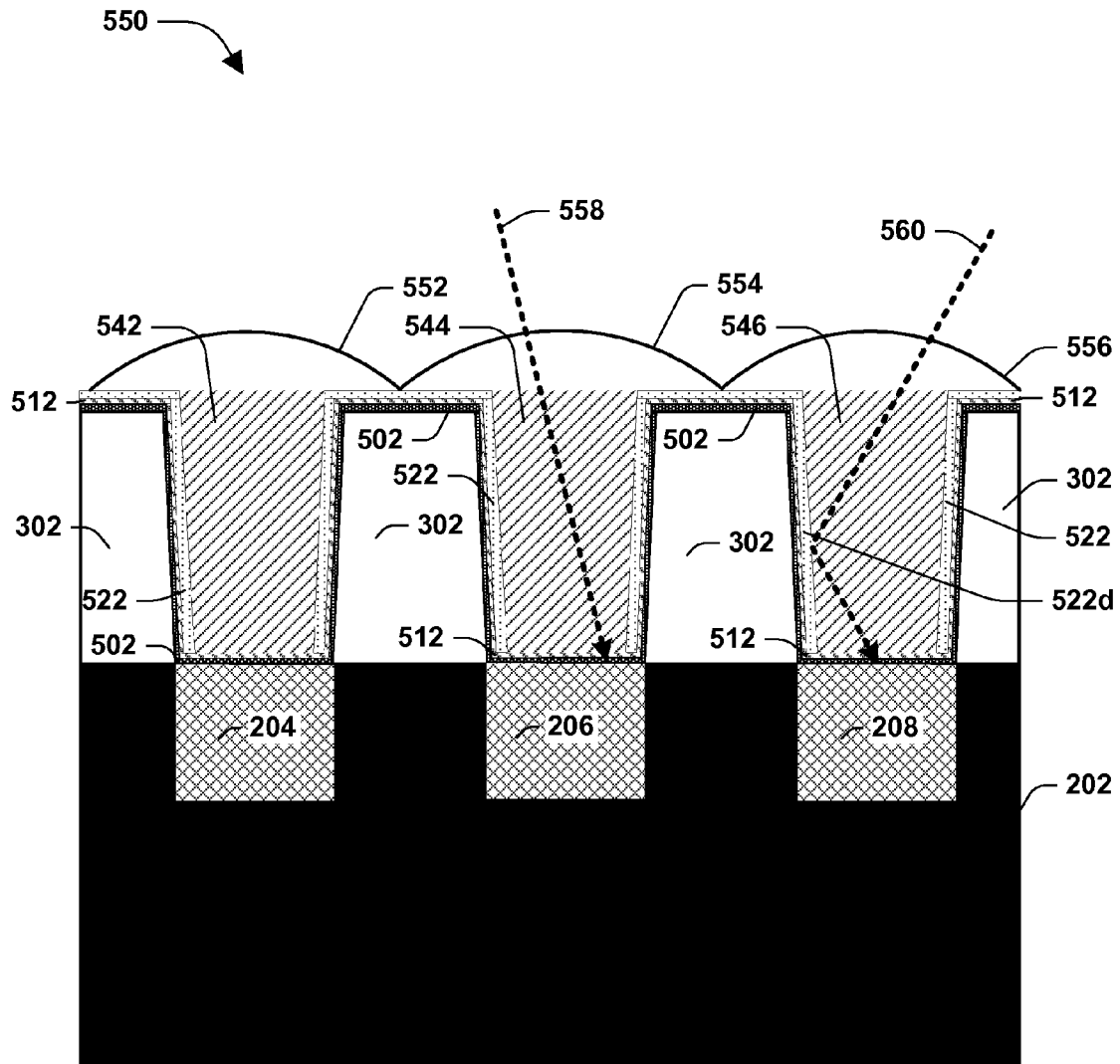


FIG. 5F

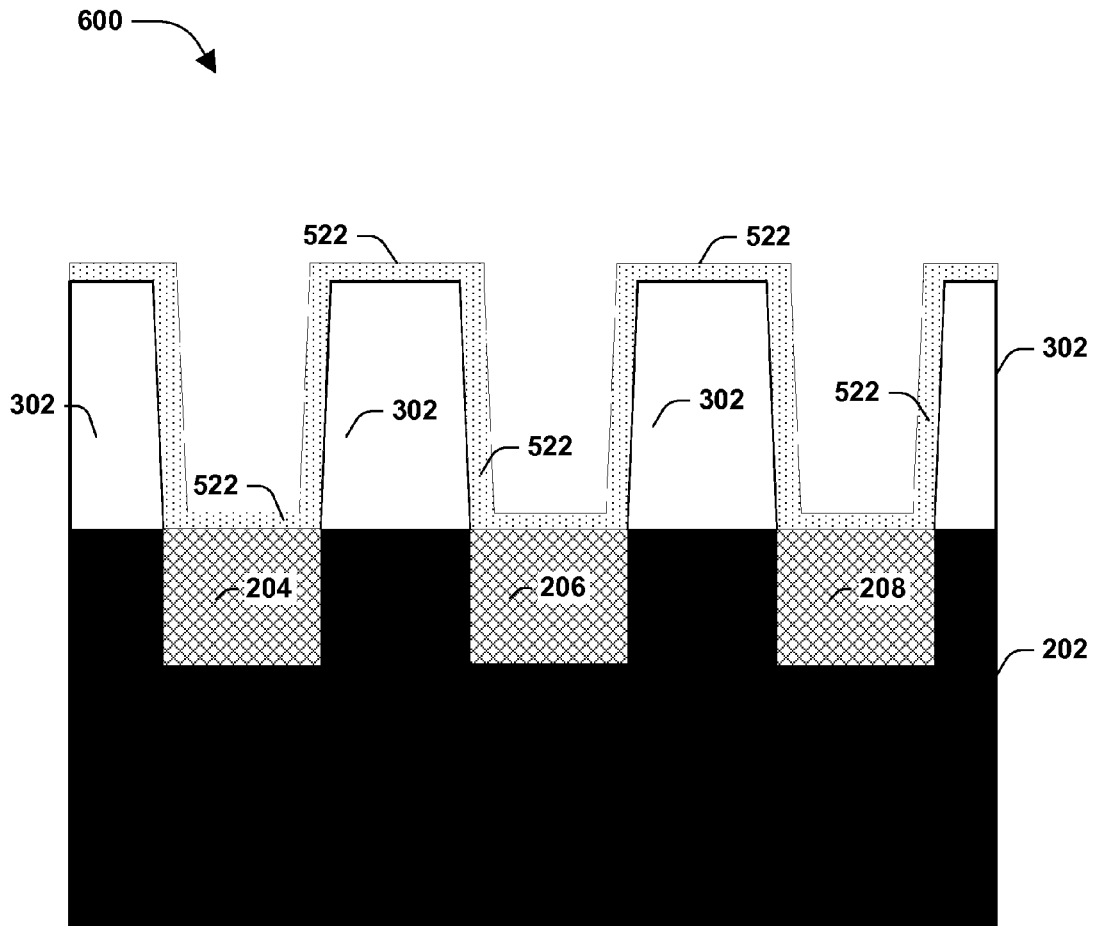


FIG. 6A

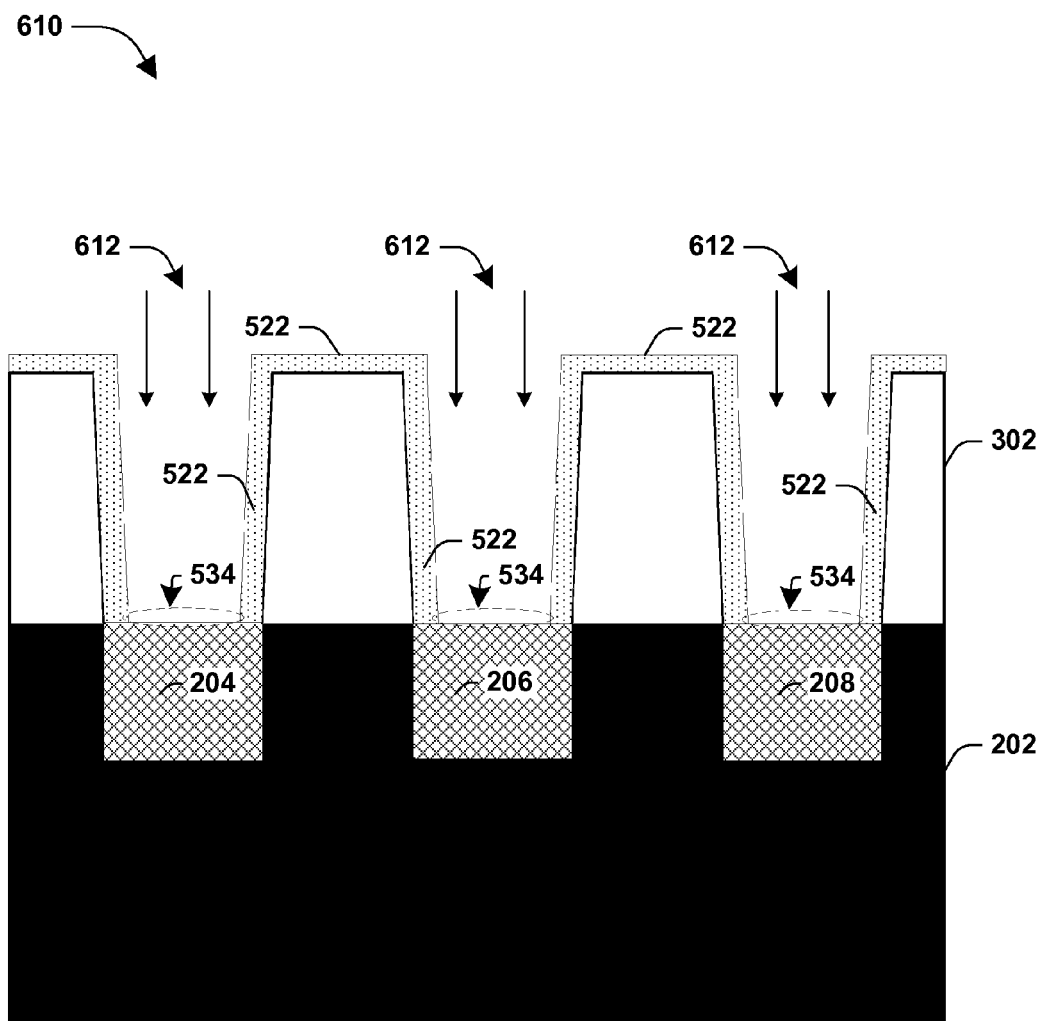


FIG. 6B

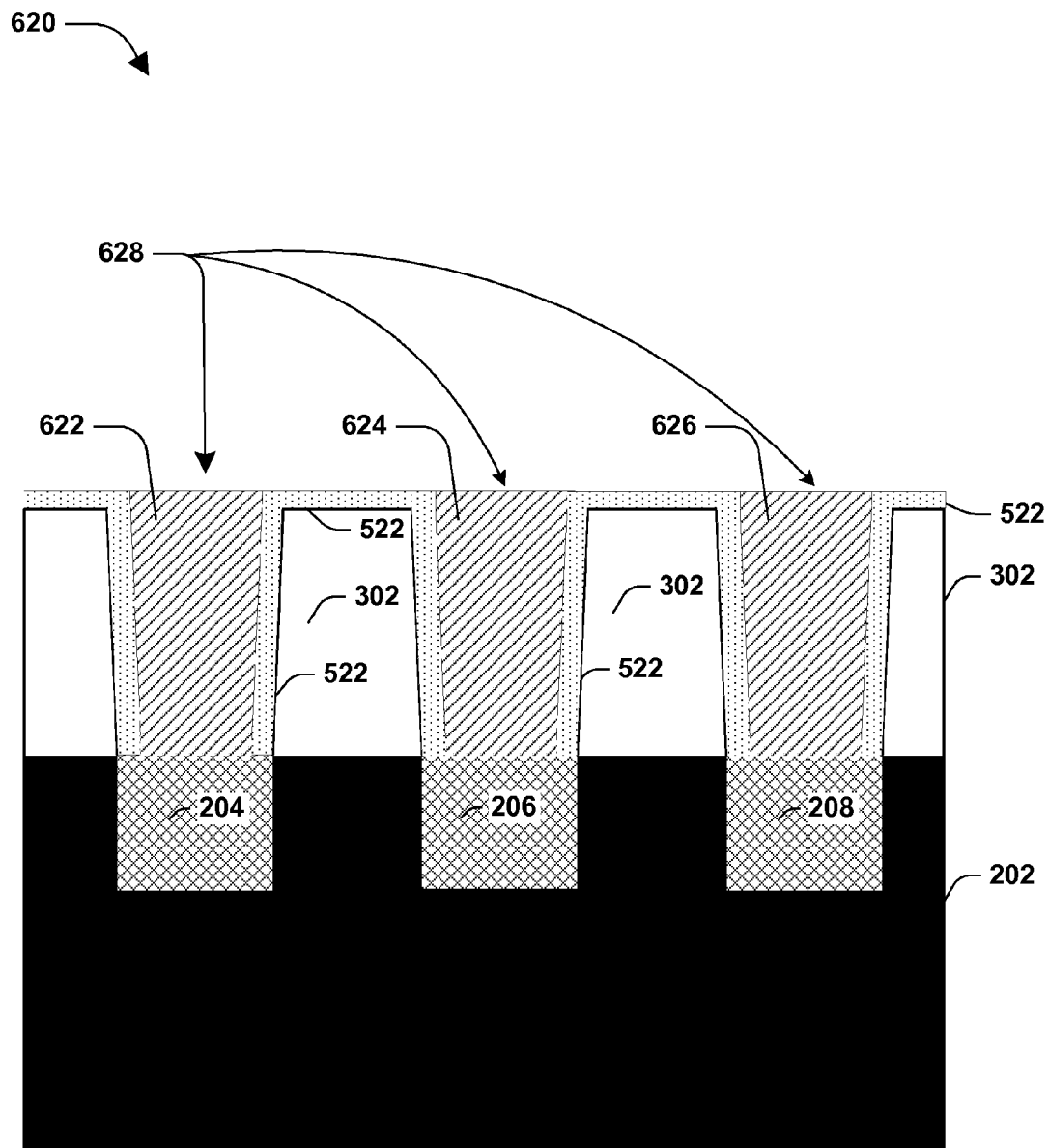


FIG. 6C

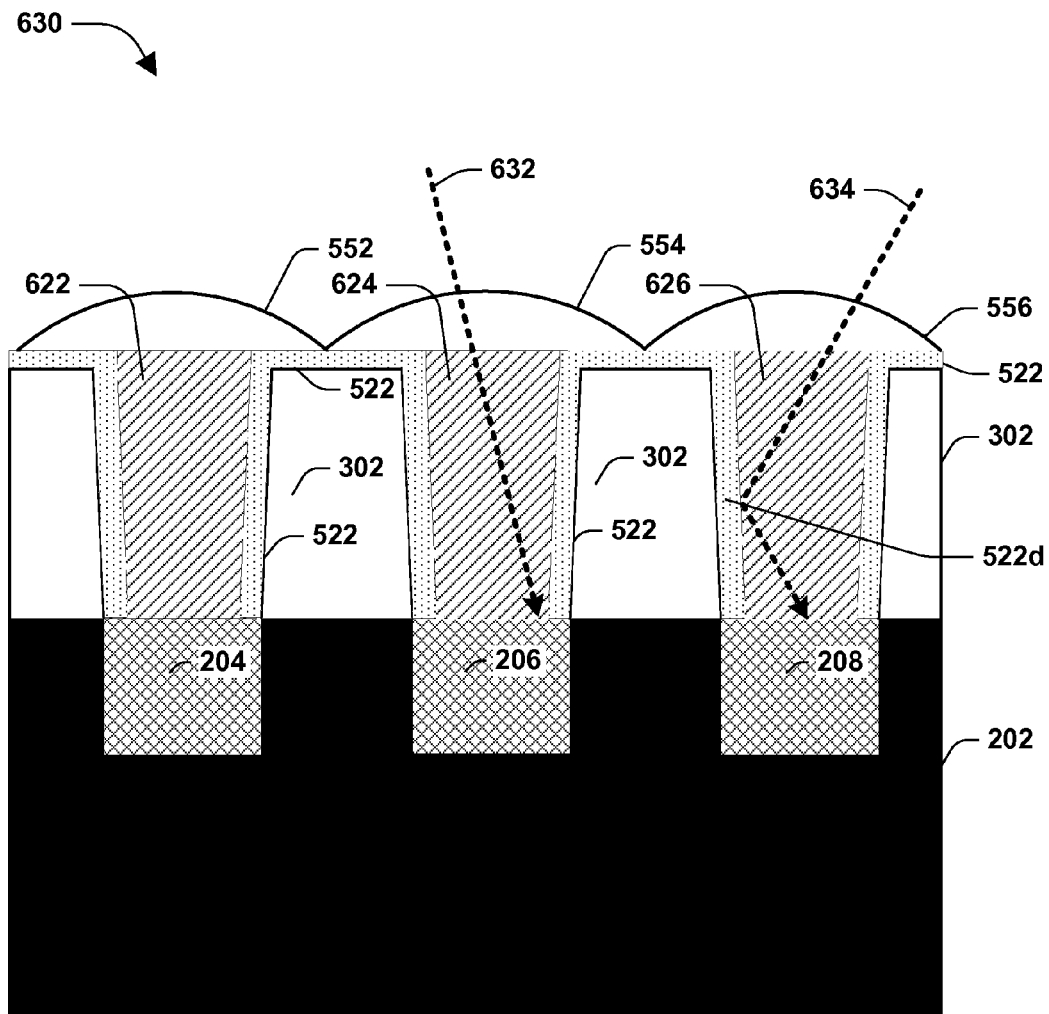


FIG. 6D

1

IMAGE SENSOR WITH TRENCHED FILLER GRID WITHIN A DIELECTRIC GRID INCLUDING A REFLECTIVE PORTION, A BUFFER AND A HIGH-K DIELECTRIC

BACKGROUND

An image sensor is used to convert an optical image focused on the image sensor into an electrical signal. The image sensor comprises an array of light detecting elements, such as photodiodes, where a light detecting element is configured to produce an electrical signal corresponding to an intensity of light impinging on the light detecting element. The electrical signal is used to display a corresponding image on a monitor or provide information about the optical image. In some embodiments, the image sensor is a charge-coupled device (CCD), a Complementary Metal-Oxide-Semiconductor (CMOS) image sensor device, or other type of sensor.

DESCRIPTION OF THE DRAWINGS

FIG. 1 is a flow diagram illustrating a method of forming an image sensor, according to some embodiments.

FIG. 2 is an illustration of a photodiode array of an image sensor, according to some embodiments.

FIG. 3 is an illustration of a dielectric layer of an image sensor, according to some embodiments.

FIG. 4 is an illustration of one or more trenches formed into a dielectric layer to form a dielectric grid of an image sensor, according to some embodiments.

FIG. 5A is an illustration of a high-k dielectric layer of an image sensor, according to some embodiments.

FIG. 5B is an illustration of a barrier layer of an image sensor, according to some embodiments.

FIG. 5C is an illustration of a reflective layer of an image sensor, according to some embodiments.

FIG. 5D is an illustration of removing a reflective layer portion of a reflective layer of an image sensor, according to some embodiments.

FIG. 5E is an illustration of a filler grid of an image sensor, according to some embodiments.

FIG. 5F is an illustration of a photodiode array detecting light, according to some embodiments.

FIG. 6A is an illustration of a reflective layer of an image sensor, according to some embodiments.

FIG. 6B is an illustration of removing a reflective layer portion of a reflective layer of an image sensor, according to some embodiments.

FIG. 6C is an illustration of a filler grid of an image sensor, according to some embodiments.

FIG. 6D is an illustration of a photodiode array detecting light, according to some embodiments.

DETAILED DESCRIPTION

The claimed subject matter is now described with reference to the drawings, wherein like reference numerals are generally used to refer to like elements throughout. In the following description, for purposes of explanation, numerous specific details are set forth in order to provide an understanding of the claimed subject matter. It is evident, however, that the claimed subject matter can be practiced without these specific details. In other instances, structures and devices are illustrated in block diagram form in order to facilitate describing the claimed subject matter.

2

One or more image sensors and one or more techniques for forming such image sensors are provided herein. In an example, an image sensor comprises a photodiode array formed over a substrate. The photodiode array comprises one or more photodiodes, such as image sensor pixels, configured to accumulate energy generated by light, such as from photons, of an optical image. A voltage of a photodiode can be read as an output for the optical image. In some embodiments, a photodiode is situated under one or more layers or components formed over the substrate. Because light travels along a light path that comprises such layers or components before reaching the photodiode, signal strength of the light can decay before reaching the photodiode or the light can travel towards another photodiode that is not to detect the light. For example, the light could be detected by a neighboring or adjacent photodiode, which can result in crosstalk because incorrect or multiple photodiodes are detecting light that is otherwise to be detected by a particular photodiode. Crosstalk can degrade performance of the image sensor, increase noise, and decrease signals produced by the image sensor.

Accordingly, one or more image sensors comprising a filler grid that is formed over a dielectric grid and one or more image sensors comprising a reflective layer that guides light to particular photodiodes are provided herein. In some embodiments, an image sensor comprises a dielectric layer formed over a photodiode array. One or more trenches are formed into the dielectric layer to form a dielectric grid. The one or more trenches are filled with filler material to form a filler grid. The filler grid comprises one or more filler structures, such as a first filler structure formed over a first photodiode. The first filler structure is formed substantially between a top surface of the dielectric grid and a top surface of the first photodiode, such that a light propagation path to the first photodiode does not comprise the dielectric grid. In this way, the light propagation path primarily comprises the first filler structure, which results in a relatively shorter light propagation path in order to mitigate light signal decay. In some embodiments, a reflective layer is formed between the filler grid and the dielectric grid, such that the reflective layer guides light towards particular photodiodes of the photodiode array, which mitigates crosstalk where an incorrect photodiode detects light.

A method 100 of forming an image sensor, according to some embodiments, is illustrated in FIG. 1, and one or more image sensors formed by such a methodology are illustrated in FIG. 2. A photodiode array 210 is formed over a substrate 202, such as a silicon substrate, as illustrated in example 200 of FIG. 2. The photodiode array 210 comprises one or more photodiodes, such as a first photodiode 204, a second photodiode 206, and a third photodiode 208. At 102, a dielectric layer 301 is formed over the photodiode array 210, as illustrated in example 300 of FIG. 3. The dielectric layer 301 is formed to protect the photodiode array 210, components, or layers formed beneath the dielectric layer 301. The dielectric layer 301 allows light to pass through, but a signal strength of the light can decay due to the light passing through the dielectric layer 301 before reaching the photodiode array 210. In some embodiments, the dielectric layer 301 comprises a dielectric material, such as oxide, silicon oxide (SiO), silicon nitride (SiN), silicon oxy-nitride (SiON), or other dielectric material. In some embodiments, the dielectric layer 302 is formed using chemical vapor deposition (CVD) or other techniques, such as a sputtering process. In an example, the dielectric layer 301 is formed at a thickness of about 10,000 Å or less.

3

At **104**, one or more trenches are formed into the dielectric layer **301** to create a dielectric grid **302**, as illustrated by example **400** of FIG. **4**. In some embodiments, a first trench **402** is formed within the dielectric layer **301** substantially over the first photodiode **204**, a second trench **404** is formed within the dielectric layer **301** substantially over the second photodiode **206**, and a third trench **406** is formed within the dielectric layer **301** substantially over the third photodiode **208**. In some embodiments, the one or more trenches are formed to a depth corresponding to a top portion of the photodiode array **210**, as illustrated by dashed line **408**. In an example, the one or more trenches are formed using an etching process, a photolithography process, or other process that can remove portions of the dielectric layer **301**. In some embodiments, the one or more trenches are formed with slanted edges, as illustrated by example **400** of FIG. **4**. In some embodiments, the one or more trenches are formed with substantially vertical edges based upon pressure or gas concentrations used during etching.

In some embodiments, a high-k dielectric layer **502** is formed over the dielectric grid **302** and the photodiode array **210**, as illustrated by example **500** of FIG. **5A**. The high-k dielectric layer **502** mitigates noise when the image sensor is switched on or off. That is, one or more dangling bonds can form between the photodiode array **210** and a layer formed above the photodiode array **210**. For example, the dangling bonds comprise electrons or other particles that result from CVD or other processing. The high-k dielectric layer **502** can mate with the dangling bonds so that electrons or other particles do not create noise. In some embodiments, the high-k dielectric layer **502** is formed by a sputter process, a physical vapor deposition (PVD), CVD, or other process. In some embodiments, the high-k dielectric layer **502** comprises a dielectric material having k value of about 20 or more. In some embodiments, the high-k dielectric layer **502** is formed to a thickness of about 100 nm.

In some embodiments, a buffer layer **512** is formed over the dielectric layer **302** and the photodiode array **210**, such as over the high-k dielectric layer **502**, as illustrated by example **510** of FIG. **5B**. The buffer layer **512** protects the high-k dielectric layer **502** during subsequent processing, such as during an etching process used to remove material, such as a reflective layer portion **534** illustrated in FIG. **5D**, that could otherwise block a light propagation path to the photodiode array **210**. In some embodiments, the buffer layer **512** is formed using CVD or other process. In some embodiments, the buffer layer **512** is formed to a thickness of about 100 nm. In some embodiments, the buffer layer **512** comprises an oxide material.

At **106**, a reflective layer **522** is formed within the one or more trenches, such as the first trench **402**, the second trench **404**, and the third trench **406** illustrated in FIG. **4**, and the reflective layer **522** is formed over the dielectric grid **302**. For example, the reflective layer **522** is formed over the buffer layer **512**, as illustrated by example **520** of FIG. **5C**. The reflective layer **522** comprises a material having a relatively high reflectivity that is capable of guiding, such as reflecting, light substantially towards corresponding photodiodes of the photodiode array **210**. For example, the reflective layer **522** comprises a metal, such as aluminum. In some embodiments, the reflective layer **522** is formed by a sputtering process, CVD, a plating process, or other process. In some embodiments, the reflective layer **522** has a relatively uniform thickness, such as a thickness of about 2,000 Å. In an example, the reflective layer **522** has a first reflective portion **522a** configured to guide light towards the first photodiode **204**, and reflect the light away from the

4

second photodiode **206**. In another example, the reflective layer **522** has a second reflective portion **522b** configured to guide light towards the third photodiode **208**, and reflect the light away from the second photodiode **206**. In this way, the reflective layer **522** has one or more reflective portions configured to guide, such as reflect or channel, light to corresponding photodiodes.

At **108**, a reflective layer portion **534** that is formed over respective photodiodes of the photodiode array **210** is removed, as illustrated in example **530** of FIG. **5D**. In this way, the reflective layer **522** is not formed over respective photodiodes of the photodiode array **210** so that a light propagation path to the photodiode array **210** is not blocked. In some embodiments, a mask is used to cover portions of the reflective layer **522** that are not to be removed by an etching process **532** used to remove the reflective layer portion **534**, such as portions of the reflective layer **522** formed over a top surface and vertical sides of the dielectric grid **302**. In some embodiments, a dry etching process is used to remove the reflective layer portion **534**.

In some embodiments, a filler grid **548** is formed over the reflective layer **522**, as illustrated by example **540** of FIG. **5E**. The filler grid **548** is formed over respective photodiodes of the photodiode array **210**. For example, a first filler structure **542** is formed substantially over the first photodiode **204**, a second filler structure **544** is formed substantially over the second photodiode **206**, and a third filler structure **546** is formed substantially over the third photodiode **208**. It will be appreciated that the filler grid **548** is formed on the buffer layer **512** in areas where reflective layer portions **534** are removed, as illustrated in FIG. **5D**. Similarly, in an embodiment where the buffer layer **512** is not formed, the filler grid **548** is formed on the high-k dielectric layer **502**, and in an embodiment where the high-k dielectric layer **502** is not formed, the filler grid **548** is formed on the photodiodes. In some embodiments, the filler grid **548** is formed between a top surface of the buffer layer **512** that covers respective photodiodes of the photodiode array **210** and a top surface of the reflective layer **522** over the dielectric grid **302**. In an embodiment, the filler grid **548** is thus slightly taller than the dielectric grid **302**, such that a top surface of the filler grid **548** is a farther distance away from a top surface of the substrate than a top surface of the dielectric grid **302** is away from the top surface of the substrate **202**. It will be appreciated, however, that the filler grid **548** can be formed to have any desired height or other dimensions. The first filler structure **542** provides a light propagation path to the first photodiode **204**. The light propagation path does not comprise the dielectric grid **302** because the dielectric grid **302** is not situated between the first filler structure **542** and the first photodiode **204**. In this way, the light propagation path is primarily through the first filler structure **542**, which can mitigate decay of a signal strength of light traveling to the first photodiode **204**. In some embodiments, the filler grid **548** is formed by a spin coating process or other process. In some embodiments, a filler structure comprises a dielectric material, an organic material, a polymer, a color filter material that allows particular wavelengths of light to pass there-through, or any other fill material.

In some embodiments, at least some different filler structures are configured to allow different colors or wavelengths of light to pass there-through. For example, the first filler structure **542** is configured to allow red light, or wavelengths corresponding to red-light, to pass there-through, but substantially no other colors of light; the second filler structure **544** is configured to allow blue light, or wavelengths cor-

5

responding to blue-light, to pass there-through, but substantially no other colors of light; the third filler structure **546** is configured to allow green light, or wavelengths corresponding to green-light, to pass there-through, but substantially no other colors of light, etc. In some embodiments, the first photodiode **204** detects red light, the second photodiode **206** detects blue light, and the third photodiode **208** detects green light. In some embodiments, other photodiodes detect other colors of light. In some embodiments, such as where different filler structures allow different colors to pass there-through, multiple processes are used to form the filler grid **542**. For example, a first process is used to form the first filler structure **542**, where areas where the second and third filler structures **544**, **546** exist or are to be formed are masked off; a second process is used to form the second filler structure **544**, where areas where the first and third filler structures **542**, **546** exist or are to be formed are masked off; a third process is used to form the third filler structure **546**, where areas where the first and second filler structures **542**, **544** exist or are to be formed are masked off, etc.

In some embodiments, one or more lens structures, such as micro lenses, are formed over the filler grid **548**, as illustrated by example **550** of FIG. 5F. For example, a first lens structure **552** is formed substantially over the first filler structure **542**, a second lens structure **554** is formed substantially over the second filler structure **544**, and a third lens structure **556** is formed substantially over the third filler structure **546**.

In an example of detecting light, light **558** passes through the second lens structure **554**, as illustrated by example **550** of FIG. 5F. The light **558** travels through the second filler structure **544** to the second photodiode **206**, and is detected by the second photodiode **206**. In some embodiments, the light **558** passes through the barrier layer **512** and the high-k dielectric layer **502** before reaching the second photodiode **206**. Because the light propagation path of the light **558** primarily corresponds to the second filler structure **544** and not the dielectric grid **302**, signal strength decay of the light **558** before detection by the second photodiode **206** is mitigated as compared to a light propagation path that passes through other layers, such as the dielectric grid **302**. Thus, the second photodiode **206** can detect a relatively strong signal from the light **558**, which improves a signal-to-noise ratio of the image sensor.

In another example of detecting light, light **560** passes through the third lens structure **556**, as illustrated by example **550** of FIG. 5F. The light **560** travels through the third filler structure **546** and encounters a surface of a reflective portion **522d** formed between the barrier layer **512** and the third filler structure **546**. Because the reflective portion **522d** has a relatively high reflectance relative to the third filler structure **546**, the light **560** is reflected towards the third photodiode **208** and away from the second photodiode **206**. Because the reflective portion **522d** channels the light **560** towards the third photodiode **208** and away from the second photodiode **206**, crosstalk between photodiodes is mitigated because the second photodiode **206** does not incorrectly detect the light **560** that is to be detected by the third photodiode **208**, thus improving the signal-to-noise ratio of the image sensor because of a decrease in error or loss of signal. Because the light propagation path of the light **560** primarily corresponds to the third filler structure **546** and not the dielectric grid **302**, signal strength decay of the light **560** before detection by the third photodiode **208** is mitigated as compared to a light propagation path that passes through other layers, such as the dielectric grid **302**. Thus,

6

the third photodiode **208** can detect a relatively strong signal from the light **560**, which can improve a signal-to-noise ratio of the image sensor.

In some embodiments, the image sensor does not comprise a high-k dielectric layer **502** and/or the barrier layer **512**, as illustrated in example **600** of FIG. 6A. That is, the high-k dielectric layer **502** and/or the barrier layer **512** can be optionally formed or not formed, according to some embodiments. In an example, the one or more trenches are formed within the dielectric layer **301** to create a dielectric grid **302**, as illustrated in example **400** of FIG. 4. The reflective layer **522** is formed over the dielectric grid **302** and over respective photodiodes of the photodiode array **210**, as illustrated in example **600** of FIG. 6A. In some embodiments, a reflective layer portion **534** that is formed over respective photodiodes of the photodiode array **210** is removed, as illustrated in example **610** of FIG. 6B. For example, an etching process **612** is performed to remove the reflective layer portion **534**. In this way, the reflective layer **522** is not formed over respective photodiodes of the photodiode array **210** so that light can reach and be detected by such photodiodes.

In some embodiments, a filler grid **628** is formed over respective photodiodes of the photodiode array **210**, as illustrated in example **620** of FIG. 6C. For example, a first filler structure **622** is formed substantially over the first photodiode **204**, a second filler structure **624** is formed substantially over the second photodiode **206**, and a third filler structure **626** is formed substantially over the third photodiode **208**. In some embodiments, respective filler structures of the filler grid **628** are formed substantially between top surfaces of respective photodiodes and a top surface of the reflective layer **522** that is portions of the dielectric grid **302**. For example, the first filler structure **622** is formed substantially between a top surface of the first photodiode **204** and the top surface of the reflective layer **522** over the dielectric grid **302**. The first filler structure **622** provides a light propagation path that primarily corresponds to the first filler structure **622**, but not the dielectric grid **302**. In some embodiments, one or more lens structures are formed over the filler grid **628**, as illustrated in example **630** of FIG. 6D.

In an example of detecting light, light **632** passes through the second lens structure **554**, as illustrated by example **630** of FIG. 6D. The light **632** travels through the second filler structure **624** to the second photodiode **206**, and is detected by the second photodiode **206**. Because the light propagation path of the light **632** primarily corresponds to the second filler structure **624** and not the dielectric grid **302**, signal strength decay of the light **632** before detection by the second photodiode **206** is mitigated as compared to a light propagation path that passes through other layers, such as the dielectric grid **302**. Thus, the second photodiode **206** can detect a relatively strong signal from the light **632**, which can improve a signal-to-noise ratio of the image sensor.

In another example of detecting light, light **634** passes through the third lens structure **556**, as illustrated by example **630** of FIG. 6D. The light **634** travels through the third filler structure **626** and encounters a surface of a reflective portion **522d** formed between the dielectric grid **302** and the third filler structure **626**. Because the reflective portion **522d** has a relatively high reflectance relative to the third filler structure **626**, the light **634** is reflected towards the third photodiode **208** and away from the second photodiode **206**. Because the reflective portion **522d** channels the light **634** towards the third photodiode **208** and away from the second photodiode **206**, crosstalk between photodiodes

is mitigated because the second photodiode **206** does not incorrectly detect the light **634** that is to be detected by the third photodiode **208**, thus improving the signal-to-noise ratio of the image sensor because of a decrease in error or loss of signal. Because the light propagation path of the light **634** primarily corresponds to the third filler structure **626** and not the dielectric grid **302**, signal strength decay of the light **634** before detection by the third photodiode **208** is mitigated as compared to a light propagation path that passes through other layers, such as the dielectric grid **302**. Thus, the third photodiode **208** can detect a relatively strong signal from the light **634**, which can improve a signal-to-noise ratio of the image sensor.

According to an aspect of the instant disclosure, an image sensor is disclosed. The image sensor comprises a photodiode array formed over a substrate. The image sensor comprises a dielectric grid that is formed over the photodiode array. The image sensor comprises a filler grid formed over the dielectric grid. The filler grid comprises one or more filler structures, such as a first filler structure formed over a first photodiode of the photodiode array. The first filler structure is formed substantially between a top surface of the dielectric grid and the first photodiode. The first filler structure provides a light propagation path to the first photodiode that primarily corresponds to the first filler structure as opposed to other layers or structures of the image sensor.

According to an aspect of the instant disclosure, an image sensor is disclosed. The image sensor comprises a photodiode array formed over a substrate. The image sensor comprises a dielectric grid that is formed over the photodiode array. The image sensor comprises a reflective layer formed over the dielectric grid, but not over respective photodiodes of the photodiode array. The reflective layer comprises one or more reflective portions configured to guide light towards corresponding photodiodes. For example, the reflective layer comprises a first reflective portion configured to guide light towards a first photodiode and reflective light away from a second photodiode.

According to an aspect of the instant disclosure, a method for forming an image sensor is provided. The method comprises forming a dielectric grid over a photodiode array comprised within a substrate. One or more trenches are formed into the dielectric layer to form a dielectric grid. The one or more trenches are formed over respective photodiodes of the photodiode array. A reflective layer is formed within the one or more trenches and over the dielectric grid. The reflective layer comprises one or more reflective portions configured to guide light towards corresponding photodiodes. For example, the reflective layer comprises a first reflective portion configured to guide light towards a first photodiode and reflective light away from a second photodiode. A reflective layer portion that is formed over respective photodiodes of the photodiode array is removed. In this way, a filler grid can be formed substantially over respective photodiodes of the photodiode array, such that light can propagate through the filler grid to corresponding photodiodes.

Although the subject matter has been described in language specific to structural features or methodological acts, it is to be understood that the subject matter of the appended claims is not necessarily limited to the specific features or acts described above. Rather, the specific features and acts described above are disclosed as example forms of implementing the claims.

Various operations of embodiments are provided herein. The order in which some or all of the operations are

described should not be construed as to imply that these operations are necessarily order dependent. Alternative ordering will be appreciated by one skilled in the art having the benefit of this description. Further, it will be understood that not all operations are necessarily present in each embodiment provided herein. It will be appreciated that layers, features, elements, etc. depicted herein are illustrated with particular dimensions relative to one another, such as structural dimensions or orientations, for example, for purposes of simplicity and ease of understanding and that actual dimensions of the same differ substantially from that illustrated herein, in some embodiments. Additionally, a variety of techniques exist for forming the layers features, elements, etc. mentioned herein, such as etching techniques, implanting techniques, doping techniques, spin-on techniques, sputtering techniques such as magnetron or ion beam sputtering, growth techniques, such as thermal growth or deposition techniques such as chemical vapor deposition (CVD), physical vapor deposition (PVD), plasma enhanced chemical vapor deposition (PECVD), or atomic layer deposition (ALD), for example.

Further, unless specified otherwise, “first,” “second,” or the like are not intended to imply a temporal aspect, a spatial aspect, an ordering, etc. Rather, such terms are merely used as identifiers, names, etc. for features, elements, items, etc. For example, a first channel and a second channel generally correspond to channel A and channel B or two different or two identical channels or the same channel.

Moreover, “exemplary” is used herein to mean serving as an example, instance, illustration, etc., and not necessarily as advantageous. As used in this application, “or” is intended to mean an inclusive “or” rather than an exclusive “or”. In addition, “a” and “an” as used in this application are generally to be construed to mean “one or more” unless specified otherwise or clear from context to be directed to a singular form. Also, at least one of A and B or the like generally means A or B or both A and B. Furthermore, to the extent that “includes”, “having”, “has”, “with”, or variants thereof are used in either the detailed description or the claims, such terms are intended to be inclusive in a manner similar to “comprising”.

Also, although the disclosure has been shown and described with respect to one or more implementations, equivalent alterations and modifications will occur to others skilled in the art based upon a reading and understanding of this specification and the annexed drawings. The disclosure includes all such modifications and alterations and is limited only by the scope of the following claims.

What is claimed is:

1. An image sensor, comprising:

- a photodiode array over a substrate;
- a dielectric grid over the photodiode array and comprising a first dielectric structure and a second dielectric structure;
- a reflective portion between the first dielectric structure and the second dielectric structure;
- a filler grid comprising a first filler structure between the first dielectric structure and the second dielectric structure, the first filler structure over a first photodiode of the photodiode array;
- a buffer laterally between the reflective portion and the first dielectric structure, the buffer in direct physical contact with the first filler structure and the buffer comprising a different material composition than the first dielectric structure and the second dielectric structure; and

9

- a high-k dielectric laterally between the buffer and the first dielectric structure.
2. The image sensor of claim 1, the high-k dielectric vertically between the first photodiode and the buffer.
3. The image sensor of claim 1, the buffer laterally between the first filler structure and the high-k dielectric.
4. The image sensor of claim 1, further comprising: one or more lens structures over the first filler structure.
5. The image sensor of claim 2, a sidewall of the high-k dielectric in direct physical contact with a sidewall of the first dielectric structure.
6. The image sensor of claim 1, the first filler structure comprising a color filter material laterally between the first dielectric structure and the second dielectric structure.
7. The image sensor of claim 1, the first filler structure extending above a top surface of the dielectric grid.
8. The image sensor of claim 1, wherein:
the high-k dielectric comprises a first portion surrounding sidewalls and a top surface of the first dielectric structure; and
the reflective portion comprises a first portion surrounding sidewalls and a top surface of the high-k dielectric.
9. The image sensor of claim 1, further comprising: one or more lens structures in contact with the first filler structure and in contact with the reflective portion.
10. The image sensor of claim 1, wherein:
the high-k dielectric is in contact with a top surface of the first dielectric structure;
the buffer is in contact with a top surface of the high-k dielectric;
the reflective portion is in contact with a top surface of the buffer; and
a lens structure is in contact with a top surface of the reflective portion.
11. An image sensor, comprising:
a photodiode array over a substrate;
a dielectric grid over the photodiode array and comprising a first dielectric structure and a second dielectric structure;
a reflective portion between the first dielectric structure and the second dielectric structure;
a filler grid comprising a first filler structure between the first dielectric structure and the second dielectric structure, the first filler structure over a first photodiode of the photodiode array;

10

- a buffer laterally between the reflective portion and the first dielectric structure, the buffer in direct physical contact with the first filler structure and the buffer comprising a different material composition than the first dielectric structure and the second dielectric structure; and
a high-k dielectric vertically between the first photodiode and the buffer.
12. The image sensor of claim 11, the high-k dielectric laterally between the buffer and the first dielectric structure.
13. The image sensor of claim 12, the buffer laterally between the first filler structure and the high-k dielectric.
14. The image sensor of claim 11, further comprising: one or more lens structures over the first filler structure.
15. The image sensor of claim 11, a sidewall of the high-k dielectric in direct physical contact with a sidewall of the first dielectric structure.
16. The image sensor of claim 11, the first filler structure comprising a color filter material laterally between the first dielectric structure and the second dielectric structure.
17. The image sensor of claim 11, the first filler structure extending above a top surface of the dielectric grid.
18. The image sensor of claim 11, wherein:
the high-k dielectric comprises a first portion surrounding sidewalls and a top surface of the first dielectric structure; and
the reflective portion comprises a first portion surrounding sidewalls and a top surface of the high-k dielectric.
19. The image sensor of claim 11, further comprising: one or more lens structures in contact with the first filler structure and in contact with the reflective portion.
20. The image sensor of claim 11, wherein:
the high-k dielectric is in contact with a top surface of the first dielectric structure;
the buffer is in contact with a top surface of the high-k dielectric;
the reflective portion is in contact with a top surface of the buffer; and
a lens structure is in contact with a top surface of the reflective portion.

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